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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/583,660	06/21/2006	Masatoshi Sasai	062668	3714	
38834 WESTERMA	7590 04/28/200 N. HATTORI, DANIEI		EXAM	TINER	
1250 CONNECTICUT AVENUE, NW			CHAWAN, SHEELA C		
SUITE 700 WASHINGTO	N. DC 20036		ART UNIT	PAPER NUMBER	
	,		2624		
			MAIL DATE	DELIVERY MODE	
			04/28/2009	PAPER	

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Application No. Applicant(s) SASAI, MASATOSHI 10/583,660 Office Action Summary Examiner Art Unit

		SHEELA C. CHAWAN	2624				
The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply							
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Status							
2a)□	Responsive to communication(s) filed on 21 Ju This action is FINAL. 2b)\(\overline{A}\) This Since this application is in condition for allowar closed in accordance with the practice under E	action is non-final. ace except for formal matters, pro		e merits is			
Disposit	ion of Claims						
5)□ 6)⊠ 7)□	Claim(s) 1-3 is/are pending in the application. 4a) Of the above claim(s) is/are withdrav Claim(s) is/are allowed. Claim(s) 1-3 is/are rejected. Claim(s) is/are objected to. Claim(s) are subject to restriction and/or						
Applicat	ion Papers						
10)⊠	The specification is objected to by the Examine The drawing(s) filed on 21 June 2006 is/are: a) Applicant may not request that any objection to the or Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Ex	☑ accepted or b)☐ objected to drawing(s) be held in abeyance. See on is required if the drawing(s) is obj	e 37 CFR 1.85(a). jected to. See 37 C				
Priority (ınder 35 U.S.C. § 119						
a)	Acknowledgment is made of a claim for foreign All b) Some * c) None of: 1. Certified copies of the priority documents 3. Copies of the certified copies of the priority accument application from the International Bureau See the attached detailed Office action for a list	s have been received. s have been received in Applicati ity documents have been receive (PCT Rule 17.2(a)).	on No ed in this National	Stage			
Attachmen	t(s)	4) 🗆 Intensions Summers	(BTO 412)				

- 1) Notice of Neterences used (+10-692)
 2) Notice of Draftsperson Patent Drawing Review (PTO-948)
 3) Information Disclosure Statement(s) (FTO/SD/03) Paper No(s)/Mail Date 6/21/06.
- Interview Summary (PTO-413)
 Paper No(s)/Mail Date. ______. 5) Notice of Informal Patent Application
- 6) Other:

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DETAILED ACTION

Priority

Receipt is acknowledged of papers submitted under 35 U.S.C. 119(a)-(d), which
papers have been placed of record in the file.

Information Disclosure Statement

The information disclosure statement (IDS) submitted on 6/21/06, the information disclosure statement is being considered by the examiner.

Drawings

3. The Examiner has approved drawings filed on 6/21/06.

Claim Rejections - 35 USC § 102

 The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless --

(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

Claims 1-3 are rejected under 35 U.S.C. 102(e) as being anticipated by Matsuyama et al., (US. 6,327,379 B2).

As to claim 1, Matsuyama discloses a substrate inspection apparatus for inspecting a formation state of a pattern area formed on a substrate (column 1, lines 10-12), the substrate inspection apparatus comprising:

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an inspection data generation means for generating inspection data in the inside (pattern image fig 4, element 21) and outside of a pattern area to be inspected (pattern outside is auxiliary pattern, fig 4, element 22); and

a determination means for determining whether the pattern area is defective or not defective by comparing the inspection data of the inside of the pattern area generated by the inspection data generation means with predetermined inside reference inspection data and comparing the inspection data of the outside with predetermined outside reference inspection data (fig 4, element 29, column 4, lines 42- 67, column 5, lines 1-23, column 7, lines 40- 64).

As to claim 2, Matsuyama discloses the substrate inspection apparatus according to Claim 1, wherein the type of the inspection data of the inside of the pattern area differs form the type of the inspection data of the outside (column 7,lines 55-64).

As to claim 3, Matsuyama discloses the substrate inspection apparatus according to Claim 1, wherein the inspection data of the inside of the pattern area is data about luminance and the inspection data of the outside is data about shapes (note, intensity corresponds to luminance, column 1, lines 13 – 22, column 5, lines 33 – 46, column 8, lines 19-31).

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Other prior art cited

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

Companion et al., (US. 6, 330, 354 B1) discloses method of analyzing visual inspection image data to find defects on a device.

Obara et al., (US. 6,870,169 B2) discloses method and apparatus for analyzing composition of defects.

Koso (US. 4,783,826) discloses pattern inspection system.

Kawahara et al., (US. 5, 608,816) discloses apparatus for inspecting a wiring pattern according to a micro-inspection and a macro-inspection performed in parallel.

Shikata (US. 7, 058,221 B1) discloses method of recognizing object based on a pattern matching and medium for recording computer program having same.

Tsujikawa et al., (US. 5, 555, 316) discloses inspecting apparatus of mounting state of component or printing state of cream solder in mounting line of electronic component.

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Contact Information

 Any inquiry concerning this communication or earlier communications from the examiner should be directed to Sheela C Chawan whose telephone number is. 571-272-7446. The examiner can normally be reached on Monday - Thursday 7.30 - 6.00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Vikkram Bali can be reached on 571-272-7415. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

/Sheela C Chawan/

4/23/09

Primary Examiner, Art Unit 2624